



PATENT

-1-

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Allan Rosencwaig et al.

Application No.: 09/629,407

Filed: August 1, 2000

For: MEASUREMENT OF THIN FILMS
AND BARRIER LAYERS ON
PATTERNED WAFER WITH X-RAY
REFLECTOMETRY

Confirmation No.: 6057

Group No.: 2882

Examiner: H.K. Song

SMALL ENTITY STATEMENT
37 CFR 1.27

121 Spear Street, Suite 290
San Francisco, CA 94105

M/S ISSUE FEE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited
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Box 1450, Alexandria, VA 22313-1450 on Dec. 3, 2003.
STALLMAN & POLLOCK LLP

Dated: 12/3/2004 By: Georgia K. Stith

Georgia K. Stith

Sir:

Applicant is a small entity.

Respectfully submitted,

STALLMAN & POLLOCK LLP

Date: December 3, 2003

By: Michael A. Stallman

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